

FQA8N90C_F109 N-Channel QFET[®] MOSFET 900 V, 8 A, 1.9 Ω

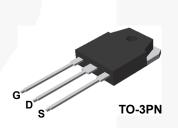
Features

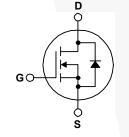
- 8 A, 900 V, $R_{DS(on)} = 1.9 \Omega$ (Max.) @ $V_{GS} = 10 V$, $I_D = 4 V$
- Low Gate Charge (Typ. 35 nC)
- Low Crss (Typ. 12 pF)
- 100% Avalanche Tested
- · RoHS Compliant

FQA8N90C_F109 — N-Channel QFET[®] MOSFET

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQA8N90C_F109	Unit
V _{DSS}	Drain-Source Voltage		900	V
I _D	Drain Current - Continuous (T _C = 25°C)		8.0	А
	- Continuous (T _C = 100°C)		5.1	А
I _{DM}	Drain Current - Pulsed	(Note 1)	32	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	850	mJ
I _{AR}	Avalanche Current	(Note 1)	8.0	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	1) 24	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.0	V/ns
P _D	Power Dissipation ($T_C = 25^{\circ}C$)		240	W
	- Derate above 25°C		1.92	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQA8N90C_F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.52	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W

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Package Marking and Ordering Information

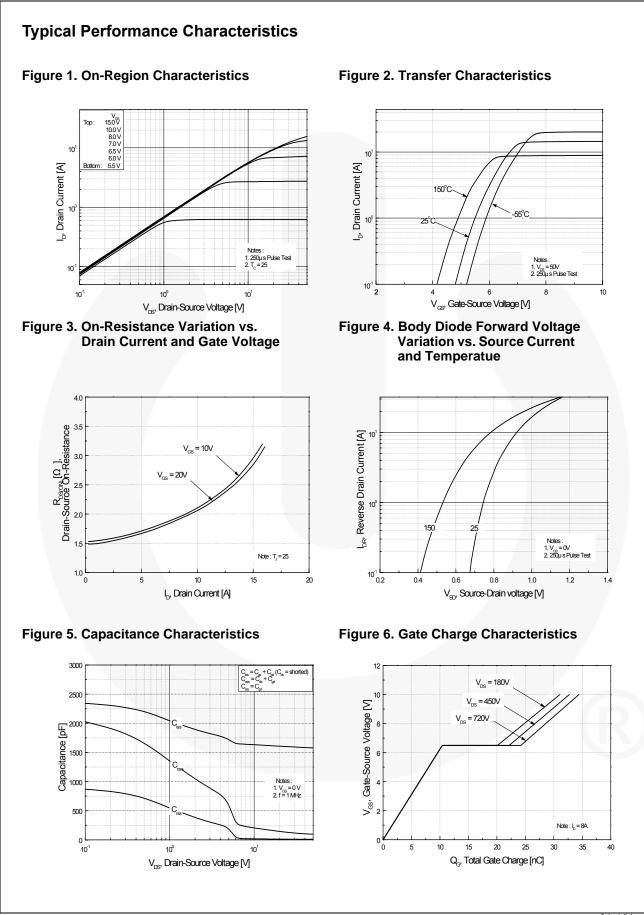
Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA8N90C_F109	FQA8N90C	TO-3PN	Tube	N/A	N/A	30 units

Electrical Characteristics T_C = 25°C unless otherwise noted.

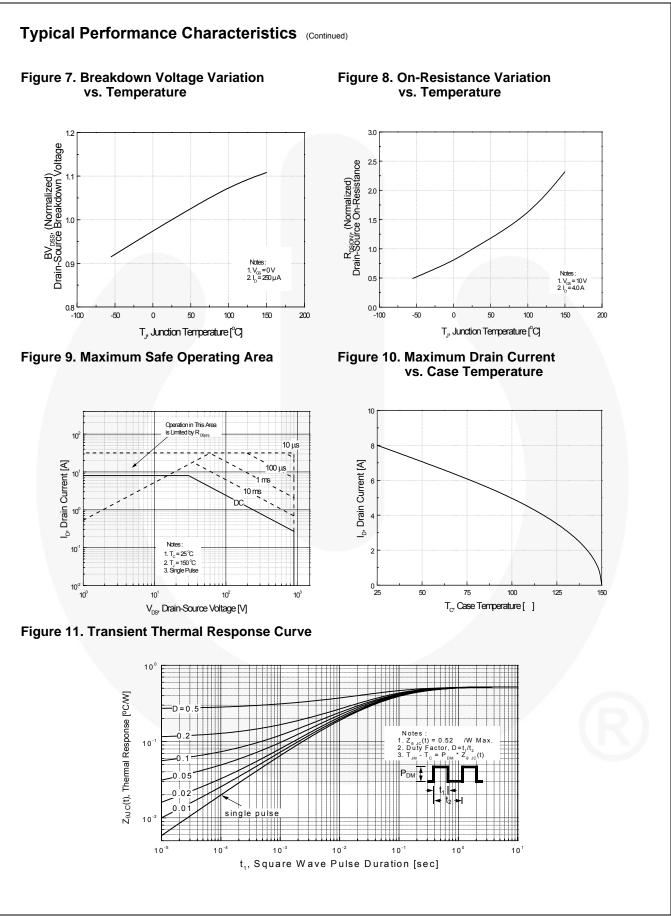
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Uni
Off Charac	teristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	900			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25° C		0.95		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 900 V, V _{GS} = 0 V			10	μA
		V _{DS} = 720 V, T _C = 125°C			100	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 30 V, V_{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V			-100	nA
On Charac	teristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.0 A		1.6	1.9	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 4.0 A		5.5		S
Dynamic C	haracteristics					
C _{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V,		1600	2080	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		130	170	pF
C _{rss}	Reverse Transfer Capacitance			12	15	pF
Switching (Characteristics					
t _{d(on)}	Turn-On Delay Time	V_{DD} = 450 V, I _D = 11.0A, R _G = 25 Ω		40	90	ns
t _r	Turn-On Rise Time			110	230	ns
t _{d(off)}	Turn-Off Delay Time			70	150	ns
t _f	Turn-Off Fall Time	(Note 4)		70	150	ns
Qg	Total Gate Charge	V _{DS} = 720 V, I _D = 11.0A,		35	45	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V	-	10		nC
Q _{qd}	Gate-Drain Charge	(Note 4)		14		nC
Drain-Sour	Lead to the construction of the constructio	3				
Is	Maximum Continuous Drain-Source Diode Fo				8.0	А
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				32.0	А
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 8.0 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 8.0 A,		530		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs		5.8		μC

 $3.I_{SD} \le 8$ A, di/dt ≤ 200 A/µs, V_{DD} $\le BV_{DSS}$, starting T_J = 25°C.

4. Essentially independent of operating temperature typical characteristics.

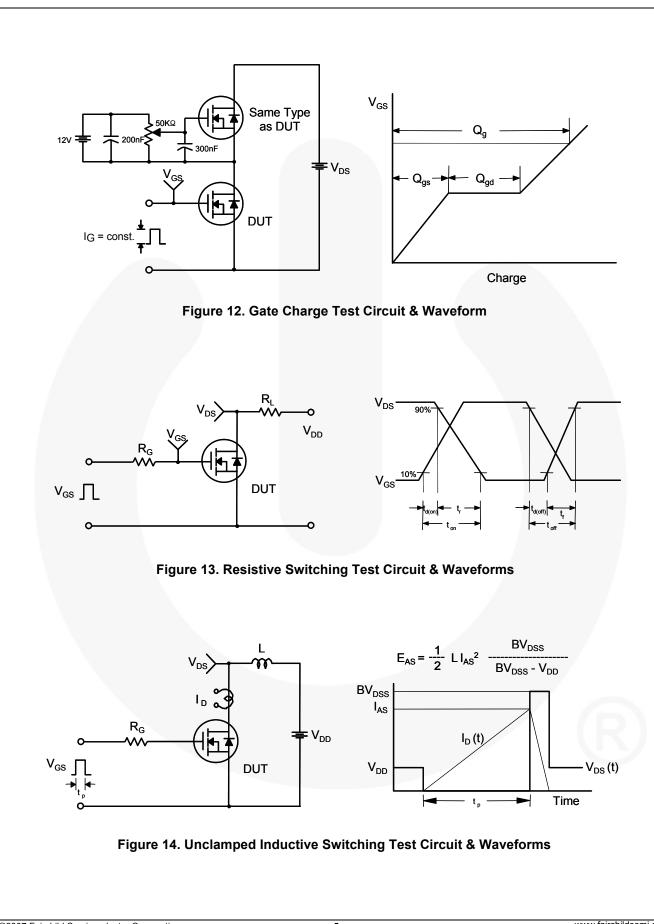


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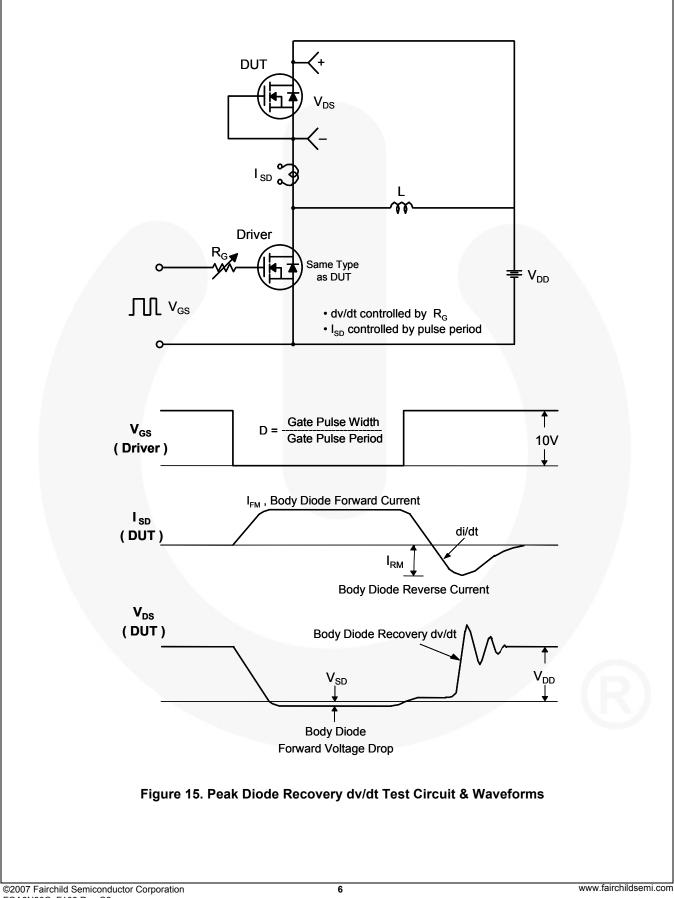


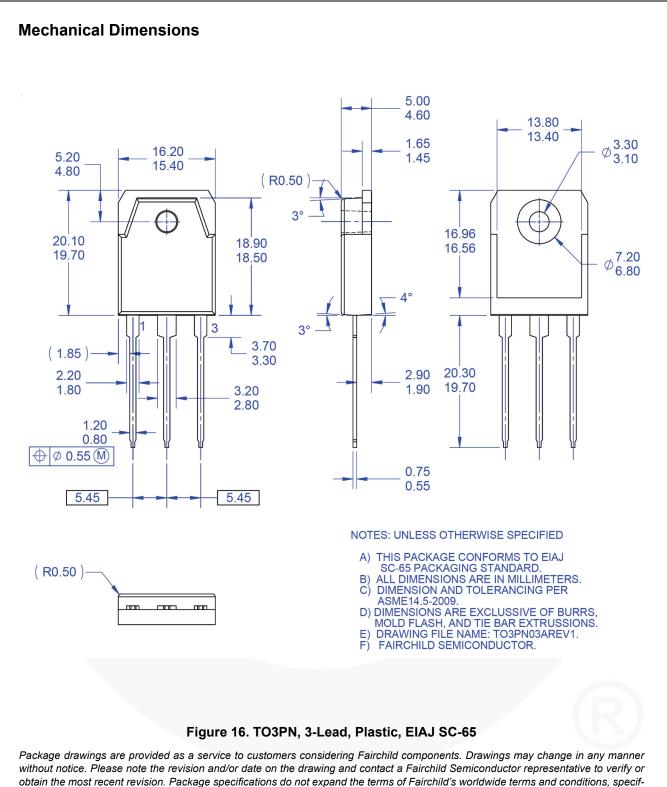
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ically the warranty therein, which covers Fairchild products.

